Se	Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/761,281	YIP ET AL.	
Examiner	Art Unit	
Afcar M. Ourochi	2667	

SEARCHED			
Class	Subclass	Date	Examiner
370	392	5/17/2005	AQ
	395.32		
	395.52		
	400		
	401		
	409		
	428		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
370	392	5/18/2005	AQ	
	395.32			
	401			

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
EAST/WEST/IEEE	5/17/2005	AQ
ACM. IP.Com		
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